





4-Heat treatment

 Heat treatments are the operations in which the wafer is simply heated and cooled to achieve specific results

Operation	Heat treatment
Patterning	Soft bake Hard bake Post exposure bake (develop)
Doping	Post ion implant anneal
Layering	Post metal deposition and patterning anneal
Figure 4.10 Table of major heat treatments	

Fabrication processes

- IC built on silicon substrate:
 - some structures diffused into substrate;
 - other structures built on top of substrate.
- Substrate regions are doped with n-type and ptype impurities. (n+ = heavily doped)
- Wires made of polycrystalline silicon (poly), multiple layers of aluminum (metal).
- Silicon dioxide (SiO₂) is insulator.



Step 1: Layering Operation. The building starts with an oxidation of the wafer surface to form a thin protective layer and to serve as a doping barrier. This silicon dioxide layer is called the *field oxide*.

Step 2: Patterning Operation. The patterning process leaves a hole in the field oxide that defines the location of the source, gate, and drain areas of the transistor.

Step 3: Layering Operation. Next, the wafer goes to an silicon dioxide oxidation operation. A thin oxide is grown on the exposed silicon. It will service as the gate oxide.

Step 4: Layering Operation. In step 4, another layering operation is used to deposit a layer of polycrystalline (poly) silicon. This layer will also become part of the gate structure.

Step 5: Patterning Operation. Two openings are patterned in the oxide/polysilicon layer to define the source and drain areas of the transistor.

Step 6: Doping Operation. A doping operation is used to create an N-type pocket in the source and drain areas.

Step 7: Layering Operation. Another oxidation/layering process is used to grow a layer of silicon dioxide over the source/drain areas.

Step 8: Patterning Operation. Holes, called contact holes, are patterned in the source, gate, and drain areas.

Step 9: Layering Operation. A thin layer of conducting metal, usually an aluminum alloy, is deposited over the entire wafer.

Step 10: Patterning Operation. After deposition, the wafer goes back to the patterning area where portions of the metallization layer are removed from the chip area and the scribe lines. The remaining portions connect all the parts of the surface components to each other in the exact pattern required by the circuit design.

Step 11: Heat Treatment Operation. Following the metal patterning step, the wafer goes through a heating process in a nitrogen gas atmosphere. The purpose of the step is to "alloy" the metal to the exposed source and drain regions and the gate region to ensure good electrical contact.

Step 12: Layering Operation. The final layer of this device is a protective layer known variously as a *scratch* or *passivation layer*. Its purpose is to protect the components on the chip surface during the testing and packaging processes, and during use.

Step 13: Patterning Operation. The last step in the sequence is a patterning process that removes portions of the scratch protection layer over the metallization terminal pads on the periphery of the chip. This step is known as the *pad mask*.



CMOS Fabrication

- · CMOS transistors are fabricated on silicon wafer
- · Lithography process similar to printing press
- On each step, different materials are deposited or etched
- Easiest to understand by viewing both top and cross-section of wafer in a simplified manufacturing process





- Substrate must be tied to GND and n-well to V_{DD}
- Metal to lightly-doped semiconductor forms poor connection called Shottky Diode
- Use heavily doped well and substrate contacts / taps



Inverter Mask Set

- Transistors and wires are defined by masks
- Cross-section taken along dashed line

























